

# PATENT ABSTRACTS OF JAPAN

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(21)Application number : 2002-066369 (71)Applicant : TOKYO ELECTRON LTD

(22)Date of filing : 12.03.2002 (72)Inventor : TAKAYAMA NAOKI  
O TAKESHI  
HARADA SATOSHI

**(54) METHOD FOR DETECTING END OF SEASONING AND PLASMA TREATMENT METHOD**

(57)Abstract:

**PROBLEM TO BE SOLVED:** To solve the problem of prior art analytic data that it is difficult to ascertain whether a variation becoming the decision criterion of the end of seasoning is a variation due to seasoning, i.e., a variation based on the state change in a treatment container, or a variation based on the temperature variation between dummy wafers and thereby it is difficult to make a decision whether seasoning has ended or not.

**SOLUTION:** The method for detecting the end of seasoning when seasoning is performed by supplying dummy wafers W into the treatment container 2 of a plasma treatment system 1 comprises a step for supplying the dummy wafers W into the treatment container 2, cooling the inside of the treatment container 2, and performing multivariate analysis using a plurality of data obtained when a plurality of dummy wafers W are supplied again into the treatment container 2 to formulate a formula for predicting the end of seasoning, and a step for detecting the end of seasoning when seasoning is

